## **REFERENCES**

## 2.4.1

- Anderson, R. & Johnson, G. G. Jr (1979). The MAX-d alphabetical index to the JCPDS data base: a new tool for electron diffraction analysis. 37th Annu. Proc. Electron Microsc. Soc. Am., edited by G. W. Bailey, pp. 444–445. Baton Rouge: Claitors.
- Avilov, A. S., Parmon, V. S., Semiletov, S. A. & Sirota, M. I. (1984). *Intensity calculations for many-wave diffraction of fast electrons in polycrystal specimens. Kristallografiya*, **29**, 11–15. [In Russian.]
- Bethe, H. A. (1928). Theorie der Beugung von Elektronen an Kristallen. Ann. Phys. (Leipzig), 87, 55–129.
- Blackman, M. (1939). On the intensities of electron diffraction rings. Proc. R. Soc. London, 173, 68-82.
- Carr, M. J., Chambers, W. F., Melgaard, D. K., Himes, V. L., Stalick, J. K. & Mighell, A. D. (1987). NBS/Sandia/ICDD Electron Diffraction Data Base. Report SAND87-1992-UC-13. Sandia National Laboratories, Albuquerque, NM 87185, USA
- Cowley, J. M & Rees, A. L. G. (1947). Refraction effects in electron diffraction. Proc. Phys. Soc. **59**, 287–302.
- Dvoryankina, G. G. & Pinsker, Z. G. (1958). *The structural study of Fe<sub>4</sub>N. Kristallografiya*, **3**, 438-445. [In Russian.]
- Goodman, P. (1963). Investigation of arsenic trisulphide by the electron diffraction radial distribution method. Acta Cryst. 16, A130.
- Grigson, C. W. B. (1962). On scanning electron diffraction. J. Electron. Control, 12, 209–232.
- Honjo, G. & Mihama, K. (1954). Fine structure due to refraction effect in electron diffraction pattern of powder sample. J. Phys. Soc. Jpn, 9, 184–198.
- Horstmann, M. & Meyer, G. (1962). Messung der Elastischen Electronenbeugungsintensitaten polykristalliner Aluminium-Schichten. Acta Cryst. 15, 271–281.
- Imamov, R. M., Pannhorst, V., Avilov, A. S. & Pinsker, Z. G. (1976). Experimental study of dynamic effects associated with electron diffraction in partly oriented films. Kristallografiya, 21. 364–369.
- International Tables for Crystallography (1993). Vol. B. Dordrecht: Kluwer Academic Publishers.
- Mighell, A. D., Himes, V. L., Anderson, R. & Carr, M. J. (1988). d-spacing and formula index for compound identification using electron diffraction. 46th Annu. Proc. Electron Microsc. Soc. Am., edited by G. W. Bailey, pp. 912–913. San Francisco Press.
- Sturkey, L. & Frevel, L. K. (1945). Refraction effects in electron diffraction. Phys. Rev. 68, 56-57.
- Tsypursky, S. I. & Drits, V. A. (1977). The efficiency of the electronometric measurement of intensities in electron diffraction structural studies. Izv. Akad. Nauk SSSR Ser. Phys. 41, 2263–2271. [In Russian.]
- Turner, P. S. & Cowley, J. M. (1969). The effect of n-beam dynamical diffraction in electron diffraction intensities from polycrystalline materials. Acta Cryst. A25, 475–481.
- Vainshtein, B. K. (1964). Structure analysis by electron diffraction. Oxford: Pergamon Press. [Translated from the Russian: Strukturnaya Electronografiya.]

## 2.4.2

Allemand, R., Bordet, J., Roudaut, E., Convert, P., Ibel, K., Jacobe, J., Cotton, J. P. & Farnoux, B. (1975). Position sensitive detectors for neutron diffraction. Nucl. Instrum. Methods, 126, 29-42.

- Caglioti, G., Paoletti, A. & Ricci, F. P. (1958). Choice of collimators for a crystal spectrometer for neutron diffraction. Nucl. Instrum. Methods, 3, 223–228.
- Carlile, C. J., Hey, P. D. & Mack, B. (1977). High efficiency Soller slit collimators for thermal neutrons. J. Phys. E, 10, 543-546
- Hewat, A. W. (1975). Design for a conventional high resolution neutron powder diffractometer. Nucl. Instrum. Methods, 127, 361–370
- Hewat, A. W. (1986a). D2B, a new high resolution neutron powder diffractometer at ILL Grenoble. Mater. Sci. Forum, 9, 69–79.
- Hewat, A. W. (1986b). High resolution neutron and synchrotron powder diffraction. Chem. Scr. 26A, 119–130.
- Hewat, A. W. & Bailey, I. (1976). D1A, a high resolution neutron powder diffractometer with a bank of Mylar collimators. Nucl. Instrum. Methods, 137, 463-471.
- Howard, C. J. (1982). The approximation of asymmetric neutron powder diffraction peaks by sums of Gaussians. J. Appl. Cryst. 15, 615–620.
- Loopstra, B. O. (1966). Neutron powder diffractometry using a wavelength of 2.6 Å. Nucl. Instrum. Methods, 44, 181–187.
- Rietveld, H. M. (1969). A profile refinement method for nuclear and magnetic structures. J. Appl. Cryst. 2, 65-71.
- Wilson, A. J. C. (1963). *Mathematical theory of X-ray powder diffractometry*. Eindhoven: Centrex.

## 2.5.1

- Besson, J. M. & Weill, G. (1992). EDX station for high pressure at LURE (DCI). High Press. Res. 8, 715-716.
- Bourdillon, A. J., Glazer, A. M., Hidaka, M. & Bordas, J. (1978). High-resolution energy-dispersive diffraction using synchrotron radiation. J. Appl. Cryst. 11, 684-687.
- Buras, B., Chwaszczewska, J., Szarras, S. & Szmid, Z. (1968). *Fixed angle scattering (FAS) method for X-ray crystal structure analysis*. Report No. 894/II/PS, 10 pp. Institute of Nuclear Research, Warsaw.
- Buras, B. & Gerward, L. (1975). Relations between integrated intensities in crystal diffraction methods for X-rays and neutrons. Acta Cryst. A31, 372-374.
- Buras, B. & Gerward, L. (1989). Application of X-ray energy-dispersive diffraction for characterization of materials under high pressure. Prog. Cryst. Growth Charact. 18, 93–138.
- Buras, B., Gerward, L., Glazer, A. M., Hidaka, M. & Olsen, J. S. (1979). Quantitative structural studies by means of the energy-dispersive method with X-rays from a storage ring. J. Appl. Cryst. 12, 531–536.
- Buras, B., Niimura, N. & Olsen, J. S. (1978). *Optimum resolution in X-ray energy-dispersive diffractometry*. J. Appl. Cryst. 11, 137–140.
- Buras, B., Olsen, J. S., Gerward, L., Selsmark, B. & Lindegaard-Andersen, A. (1975). Energy-dispersive spectroscopic methods applied to X-ray diffraction in single crystals. Acta Cryst. A31, 327-333.
- Clark, S. M. (1992). A new white beam single crystal and powder diffraction facility at the SRS. Rev. Sci. Instrum. 63, 1010–1012.
- Fukamachi, T., Hosoya, S. & Terasaki, O. (1973). The precision of interplanar distances measured by an energy-dispersive method. J. Appl. Cryst. 6, 117-122.